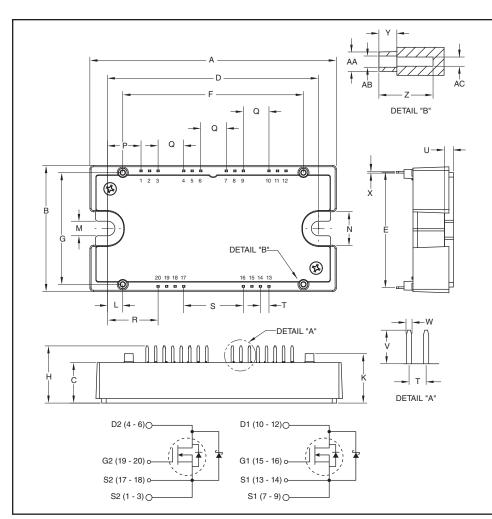


QJD1210SA1 Preliminary

Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

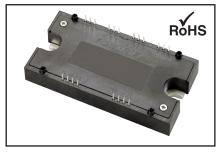


Outline Drawing and Circuit Diagram

Dimensions	Inches	Millimeters
А	4.32	109.8
В	2.21	56.1
С	0.71	18.0
D	3.70±0.02	94.0±0.5
E	2.026	51.46
F	3.17	80.5
G	1.96	49.8
Н	1.00	25.5
K	0.87	22.0
L	0.266	6.75
М	0.26	6.5
Ν	0.59	15.0
Р	0.586	14.89

Dimensions	Inches	Millimeters
Q	0.449	11.40
R	0.885	22.49
S	1.047	26.6
Т	0.15	3.80
U	0.16	4.0
V	0.30	7.5
W	0.045	1.15
Х	0.03	0.8
Y	0.16	4.0
Z	0.47	12.1
AA	0.17 Dia.	4.3 Dia.
AB	0.10 Dia.	2.5 Dia.
AC	0.08 Dia.	2.1 Dia.

Information presented is based upon manufacturers testing and projected capabilities. This information is subject to change without notice. The manufacturer makes no claim as to the suitability of use, reliability, capability, or future availability of this product. 12/14 Rev. 1



Description:

Powerex Silicon Carbide MOSFET Modules are designed for use in high frequency applications. Each module consists of two MOSFET Silicon Carbide Transistors with each transistor having a reverse connected fast recovery free-wheel silicon carbide Schottky diode. All components and interconnects are isolated from the heat sinking baseplate, offering simplified system assembly and thermal management.

Features:

- □ Silicon Carbide Chips
- □ Low Internal Inductance
- □ Industry Leading RDS(on)
- □ High Speed Switching
- Low Switching Losses
- □ Low Capacitance
- □ Low Drive Requirement□ Fast 75A Free Wheeling
- Schottky Diode
- □ Isolated Baseplate
- □ Aluminum Nitride Isolation
- 2 Individual Switches per Module
- Copper Baseplate
- □ RoHS Compliant

Applications:

- Energy Saving Power
 Systems such as:
 Fans; Pumps; Consumer
 Appliances
- High Frequency Type Power Systems such as: UPS; High Speed Motor Drives; Induction Heating; Welder; Robotics
- High Temperature Power
 Systems such as:
 Power Electronics in Electric
 Vehicle and Aviation Systems



QJD1210SA1

Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

Absolute Maximum Ratings, $T_j = 25$ °C unless otherwise specified

Ratings	Symbol	QJD1210SA1	Units	
Drain-Source Voltage (V _{GS} = -10V)	V _{DSS}	1200	Volts	
Gate-Source Voltage (D-S Short)	VGSS	±20	Volts	
Drain Current (Continuous) at T _C = 78°C	۱ _D	100	Amperes	
Drain Current (Pulsed)*1	ID(pulse)	200	Amperes	
Maximum Power Dissipation ($T_C = 25^{\circ}C, T_j < 150^{\circ}C$)	PD	520	Watts	
Junction Temperature	Tj	-40 to 150	°C	
Storage Temperature	T _{stg}	-40 to 125	°C	
Mounting Torque, M6 Mounting Screws	_	40	in-lb	
Module Weight (Typical)	_	270	Grams	
V Isolation Voltage	VRMS	3000	Volts	

*1 Pulse width and repetition rate should be such that device junction temperature (Tj) does not exceed Tj(max) rating.



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Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

MOSFET Characteristics, $T_j = 25$ °C unless otherwise specified

Characteristics	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain-Source Leakage Current*2	IDSS	$V_{GS} = -10V, V_{DS} = 1200V$	_	100	_	μA
Drain-Source Leakage Current*2	IDSS	V_{GS} = -10V, V_{DS} = 1200V, T_j = 150°C	_	200	_	μA
Gate Leakage Current	IGSS	$V_{DS} = 0, V_{GS} = \pm 20V$	_	1.0	_	μA
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = 10V, I_{D} = 34mA$	0.4	1.0	1.6	Volts
Drain-Source On Resistance (Chip)	R _{DS(on)}	$I_D = 100A, V_{GS} = 15V, T_j = 25^{\circ}C$	_	17	_	mΩ
		I _D = 100A, V _{GS} = 15V, T _j = 150°C	_	29	_	mΩ
Drain-Source On Resistance (Terminal)	R _{DS(on)}	$I_D = 100A, V_{GS} = 15V, T_j = 25^{\circ}C$	_	18	_	mΩ
		I _D = 100A, V _{GS} = 15V, T _j = 150°C	_	30	_	mΩ
Total Gate Charge	QG	$V_{CC} = 600V, I_D = 100A, V_{GS} = 0 \text{ to } 15V$	_	330	_	nC
Input Capacitance	C _{iss}		_	8.2	_	nF
Output Capacitance	C _{oss}	V _{GS} = 0, V _{DS} = 10V, f = 100 kHz	_	2.7	_	nF
Reverse Transfer Capacitance	C _{rss}		_	180	_	pF
Turn-on Delay Time	^t d(on)		_	90	_	ns
Rise Time	t _r	V _{DD} = 600V, I _D = 100A,	_	85	_	ns
Turn-off Delay Time	^t d(off)	V _{GS} = ±15V,	_	300	_	ns
Fall Time	t _f	 R _G = 18Ω, T _j = 150°C,	_	85	_	ns
Turn-on Switching Energy	Eon	Inductive Load	_	TBD	_	mJ
Turn-off Switching Energy	E _{off}		_	TBD	_	mJ

*2 Total module leakage includes MOSFET leakage plus reverse Schottky diode leakage.



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Reverse Schottky Diode Characteristics, $T_j = 25$ °C unless otherwise specified

Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Diode Forward Voltage (Chip)	V _{SD}	IF = 75A, V _{GS} = -15V, T _j = 25°C	_	1.45	1.75	Volts
	_	I _F = 75A, V _{GS} = -15V, T _j = 150°C	_	1.95	2.35	Volts
Diode Forward Voltage (Terminal)	V _{SD}	$I_F = 75A, V_{GS} = -15V, T_j = 25^{\circ}C$	_	1.55	1.85	Volts
		IF = 75A, VGS = -15V, Tj = 150°C	_	2.05	2.45	Volts
Diode Capacitive Charge	QC	V _R = 600V, I _F = 75A,	_	300	_	nC
		di/dt = 2200A/ μ s, T _j = 150°C				
Reverse Recovery Time	t _{rr}	$V_{R} = 600V, I_{F} = 75A,$	_	35	_	nS
		di/dt = 2200A/µs, Tj = 150°C				

Thermal and Mechanical Characteristics, $T_j = 25$ °C unless otherwise specified

Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Thermal Resistance, Junction-to-Case*3	R _{th(j-c)}	MOSFET Part	—	_	0.24	°C/W
Thermal Resistance, Junction-to-Case*3	R _{th(j-c)}	Diode Part	—	—	0.39	°C/W
Contact Thermal Resistance	R _{th(c-s)}	Per 1/2 Module, Thermal Grease Applied	—	0.04	—	°C/W
Internal Inductance	L _{int}	MOSFET Part	—	10	_	nH

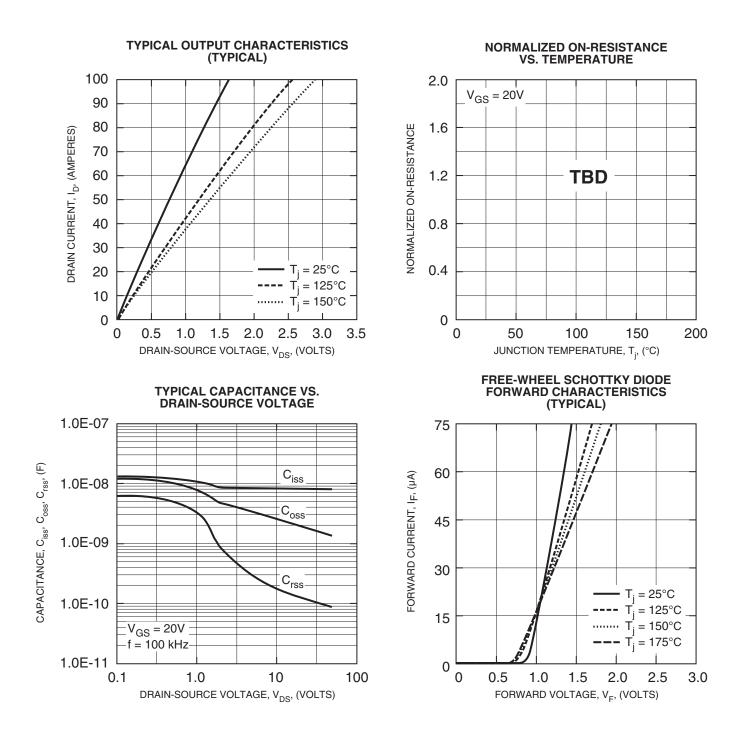
*3 Case temperature (T_C) and heatsink (T_S) are defined on the surface of the baseplate and heatsink at just under the chip.



Preliminary

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